

Notice of References Cited	Application/Control No. 10/634,044	Applicant(s)/Patent Under Reexamination SEGAWA ET AL.	
	Examiner John P. Leubecker	Art Unit 3739	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0020810 A1	01-2003	Takizawa et al.	348/68
*	B	US-2003/0137595 A1	07-2003	TAKACHI, TAIZO	348/340
*	C	US-2003/0158503 A1	08-2003	Matsumoto, Shinya	600/593
*	D	US-2003/0146998 A1	08-2003	Doering et al.	348/340
*	E	US-2004/0080658 A1	04-2004	Cambou et al.	348/340
*	F	US-6,951,536 B2	10-2005	Yokoi et al.	600/128
*	G	US-2005/0250991 A1	11-2005	Mizuno, Hitoshi	600/160
*	H	US-2006/0036131 A1	02-2006	Glukhovsky et al.	600/160
*	I	US-7,022,066 B2	04-2006	Yokoi et al.	600/109
*	J	US-2007/0152147 A1	07-2007	Webster, Steven	250/239
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.